

# Time-Interleaved ADCs, Past and Future

Ken Poulton  
*Agilent Laboratories*

# Outline

- ◆ Some History
- ◆ Reasons to Interleave
- ◆ Issues with Interleaving (with examples)
- ◆ Futures

# Some History of Interleaving

- ◆ 1980      4-way                  100 MSa/s                  4 slices/chip                  CCD (T/H)
- ◆ 1980      Corcoran & Hornak      4 MSa/s                  4 slices/chip                  CMOS
- ◆ 1980      4-way                  Hodges & Black
- ◆ 1987      4-way                  1 GSa/s                  1 slices/chip                  bipolar + GaAs
- ◆ 1987      Poultion, Corcoran & Hornak
- ◆ 1991      16-way                  8 GSa/s                  2 slices/chip                  bipolar
- ◆ 1991      Rush & Byrne
- ◆ 1997      4-way                  8 GSa/s                  2 slices/chip                  bipolar
- ◆ 1997      Poultion, Knudsen, Kerley, Kang, Tani, Cornish, VanGrouw
- ◆ 2002      32-way                  4 GSa/s                  32 slices/chip                  CMOS
- ◆ 2002      Poultion, Neff, Muto, Liu, Burstein, Heshami
- ◆ 2003      80-way                  20 GSa/s                  80 slices/chip                  CMOS
- ◆ 2003      Poultion, Neff, Setterberg, Wuppermann, Kopley, Jewett, Pernillo, Tan, Montijo
- ◆ 2008      16-way                  24 GSa/s                  64 slices/chip                  CMOS
- ◆ 2008      Schhvan, Bach, Falt, Flemk, Gibbons, Greshishchev, Hamida, Pollex, Sitch, Wang, Wolczanski
- ◆ Trends:
  - Only modest on-chip interleaving until 2002
  - Massively-parallel interleaving introduced in 2002

# Why Do Time Interleaving?

- ◆ Highest possible sample rate
  - When you max out the single-ADC sample rate in available technologies, interleaving is the way to further increase sample rate
- ◆ Reduce cost
  - Interleaving has moved multi-GSa/s ADCs from bipolar to CMOS
- ◆ Optimize power
  - CMOS ADCs are generally much more power-efficient
  - Can choose sample rate to optimize power efficiency

# Why Not?

- ◆ Interleaving Errors
  - Calibration
- ◆ Extra complexity in HW, possibly SW and system

## **Issues and Example Solutions**

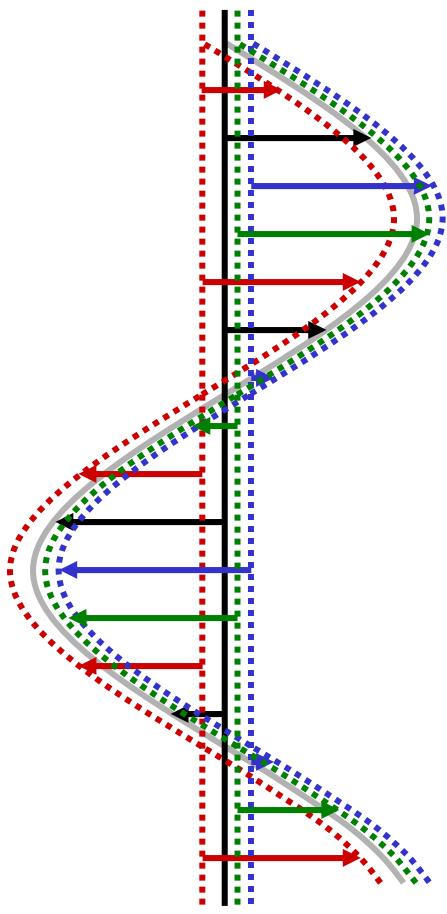
- I'll describe issues for the design of interleaved ADCs, focusing mostly on on-chip interleaving
- I'll describe some example solutions, mostly from our own work

# Core ADC Slice

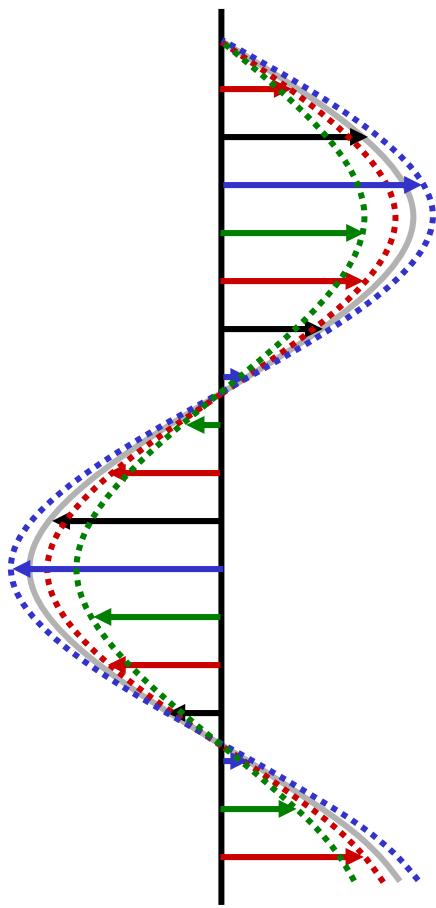
- ◆ Objectives
  - Total power optimization – there is an optimum slice sample rate for a given technology ADC architecture
  - Area
  - Metastable error rate tends to limit sample rate of multi-stage ADCs
  - Calibration – more calibration can allow smaller-area devices with more mismatch
- ◆ Two examples:

Year	1997	2002
Process	25 GHz $f_T$ Bipolar	0.35 um CMOS
Sample Rate	4 GSa/s, 7 bits	4 GSa/s, 8 bits
Slices	2x 2 GSa/s	32x 125 MSa/s
Slice Topology	Folded Flash, little calibration	Pipeline w/ per- stage calibration
Slice Power	3 W	50 mW
Chip Power	13 W	4.5 W

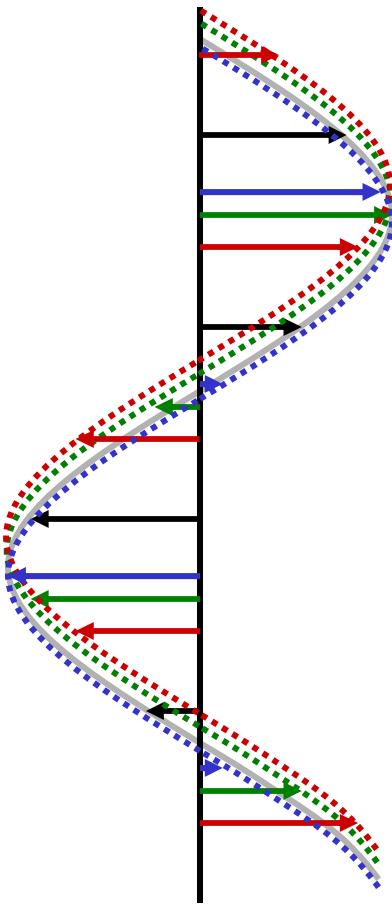
# Types of Interleaving Errors



Offset Error  
want <0.3% offsets for 8 bits



Gain Error  
want <0.3% gain matching



Sampling Instant Error  
want <1 ps timing errors  
for Fin of 1 GHz

- ◆ Errors due to mismatched paths
- ◆ Reconstructed waveform shows distortion.
- ◆ Spurs in the spectrum.

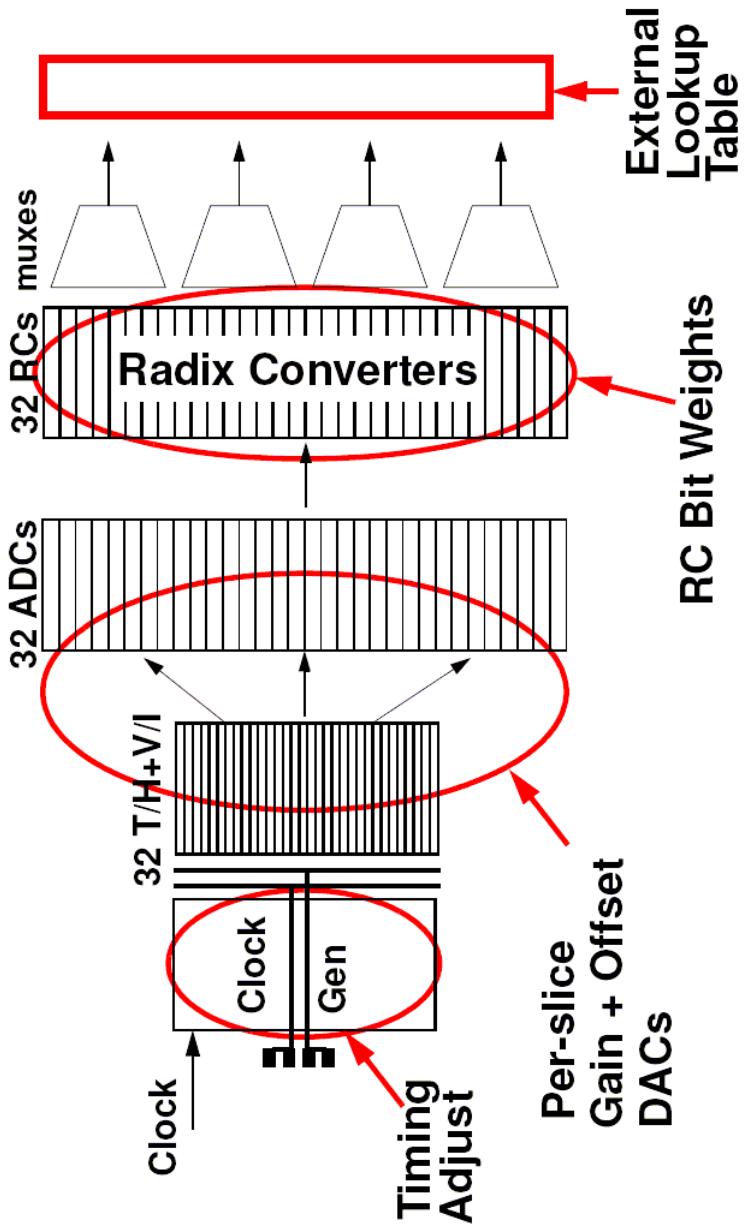
# Calibration Choices

- ◆ Calibration Approaches:
  - No Cal: Accurate by design
    - + Simplest in operation
    - Stringent matching requirements => more area, higher power
    - Risk: any unforeseen mismatch needs a mask turn to fix
  - Analog Cal: Calibrate with adjustable offset, gain and delay DACs or trims
    - + Circuit sizes limited by SNR, not matching => much reduced power
    - + Maximize signal range valid in all slices
    - + Offset and gain adjusts can be low power
    - Delay adjusts add jitter and power
    - Risk: more analog circuits to design
  - Digital Cal: Calibrate with DSP
    - + Circuit sizes limited by SNR, not matching => much reduced power
    - + Fewer analog circuits than analog cal
    - Adds more quantization noise
    - Every adjust adds active data path power
      - + Eventualy, power of digital corrections will be lower than analog
    - More digital supply noise

# More Calibration Choices

- ◆ On-chip vs off-chip calibration (coefficient computation)
  - Off Chip:
    - + lower chip cost
    - + lower design risk
    - much more HW and/or SW complexity for the ADC user
  - On Chip
    - + More generally applicable
    - Higher design cost and risk
- ◆ Foreground calibration vs. Background calibration
  - Foreground
    - + Independent of the input signal
    - ADC user needs to provide cal signals
    - Dead time during calibration
  - Background
    - + Least complexity for the ADC user
    - Places some requirements on the input signal

## Example of Calibration Choices – 32-way & 80-way CMOS ADCs



- ◆ Oscilloscope application
- ◆ Non-binary-radix pipeline
- ◆ Maximize tolerated offset
- ◆ 0.35, 0.18 um process

-> Foreground calibration

-> Off-chip calibration

-> Digital gain and offset for fine cal

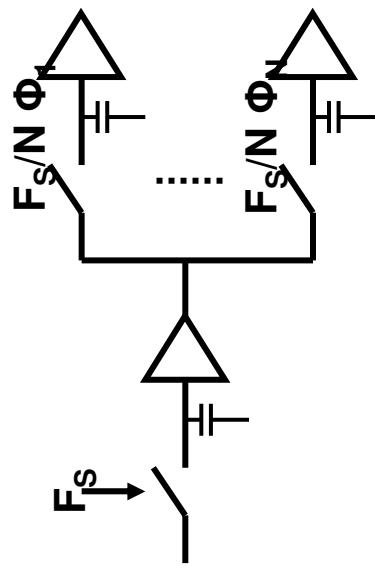
-> Analog cal for coarse gain, offset

-> Adjustable delays for timing cal

-> External lookup for linearity correction

# Sample Timing Solutions: Single Samplers

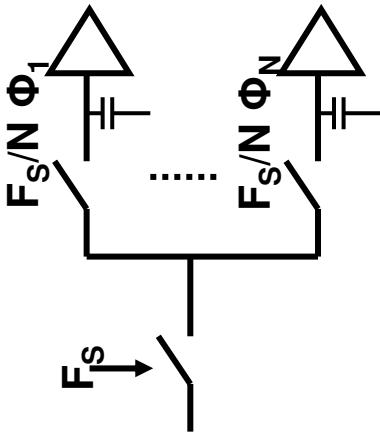
- + Relaxes slice clock accuracy requirements
- Requires a full-speed clock and sampler
  - Two topologies:



Two-Rank T/H system

- + **best T/H BW**

Corcoran, et al, ISSCC 1987



Two-Switch T/H system

- + **lower noise and power**

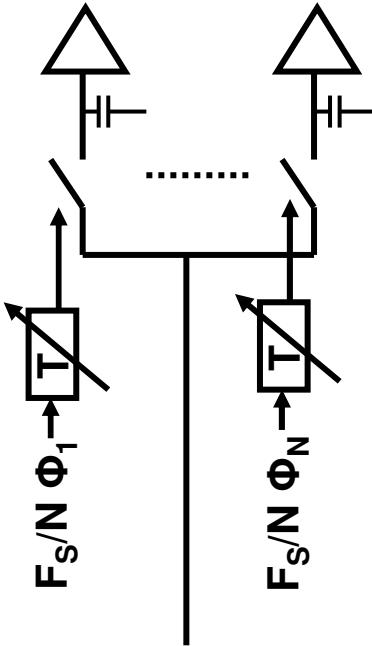
Gupta, et al, ISSCC 2007

# Sample Timing Solutions: Interleaved Samplers

- ◆ Interleaved Samplers:
  - + Nothing needs to run at  $F_S$
  - + No critical settling between T/Hs
    - Large  $C_{IN}$
    - Hard to make many equal clock and  $V_{IN}$  paths
    - Timing correction usually required

- ◆ Timing Correction Methods:

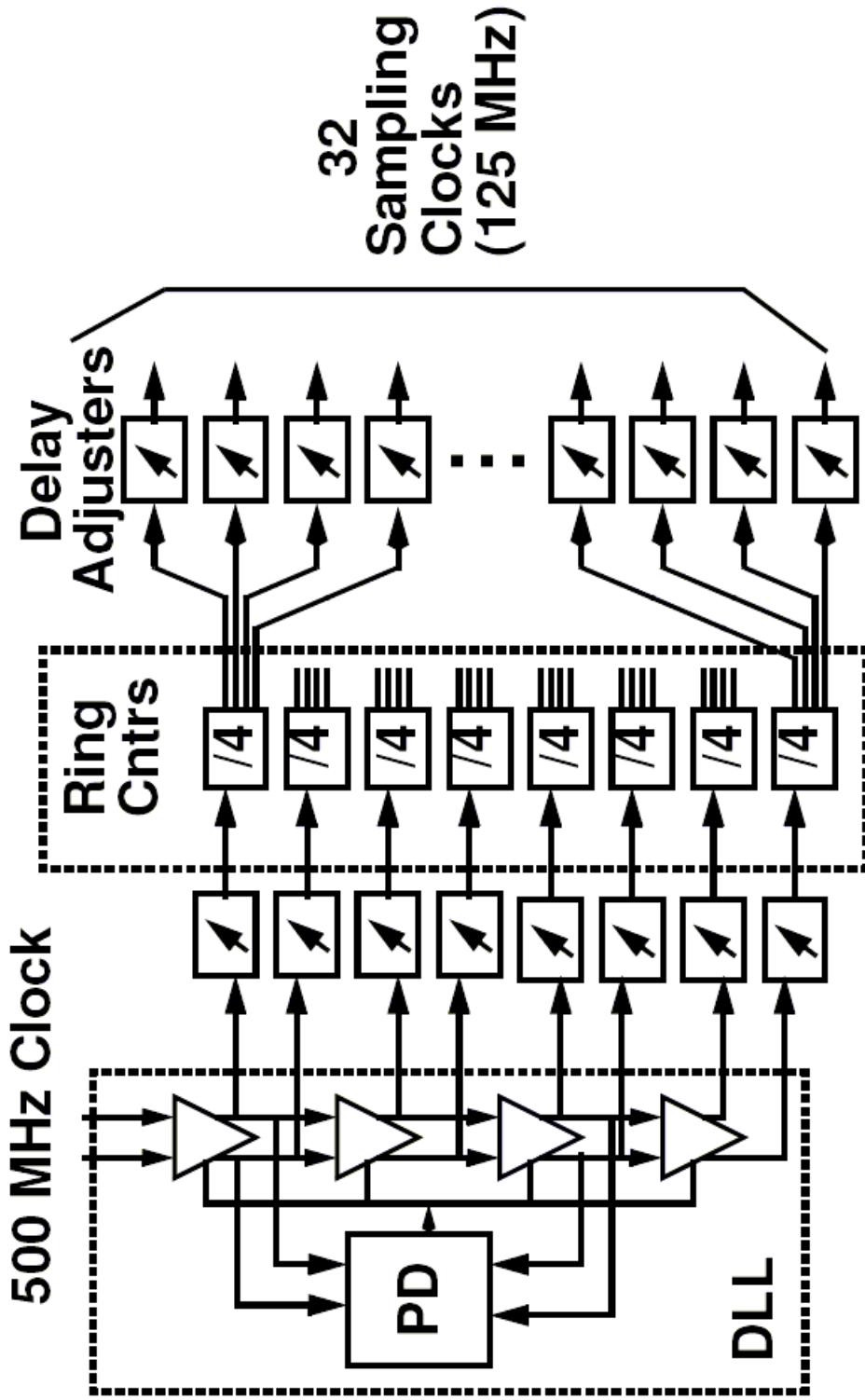
- Adjustable delays in clock paths
  - + Corrects the actual sampling instants
    - Drift
    - Delays add jitter and power
  - Poulton, et al, ISSCC 2002*
- Delay adjustment by DSP after ADC
  - + Shorter timing paths to drift
    - Timing adjust filters cause gain vs. Fin errors near Nyquist
    - Power and digital noise generation
  - Jamal, et al, ISSCC 2002*



# Accuracy of Clock Generation

- ◆ Single Front-end Sampler
  - One full-accuracy clock (0.1-1 ps rms jitter)
  - N reduced-accuracy clocks (1-10 ps rms jitter and alignment)
    - Second rank requires fairly accurate clocks due to analog settling effects
- ◆ Interleaved front-end samplers
  - N Full-accuracy clocks (0.1-1 ps rms jitter and alignment)
    - Generating lots of very-low-jitter clocks can cost a lot of power
    - Simple DLL for N clocks, constant jitter spec:
      - **N stages, with power scaling as N to maintain jitter**
      - => Power scales as  $N^2$
- ◆ For more detail, see: Robert Neff, “Clock Challenges for GHz ADCs”  
*In the Clock Synthesis Design Forum (F7) on Thursday*

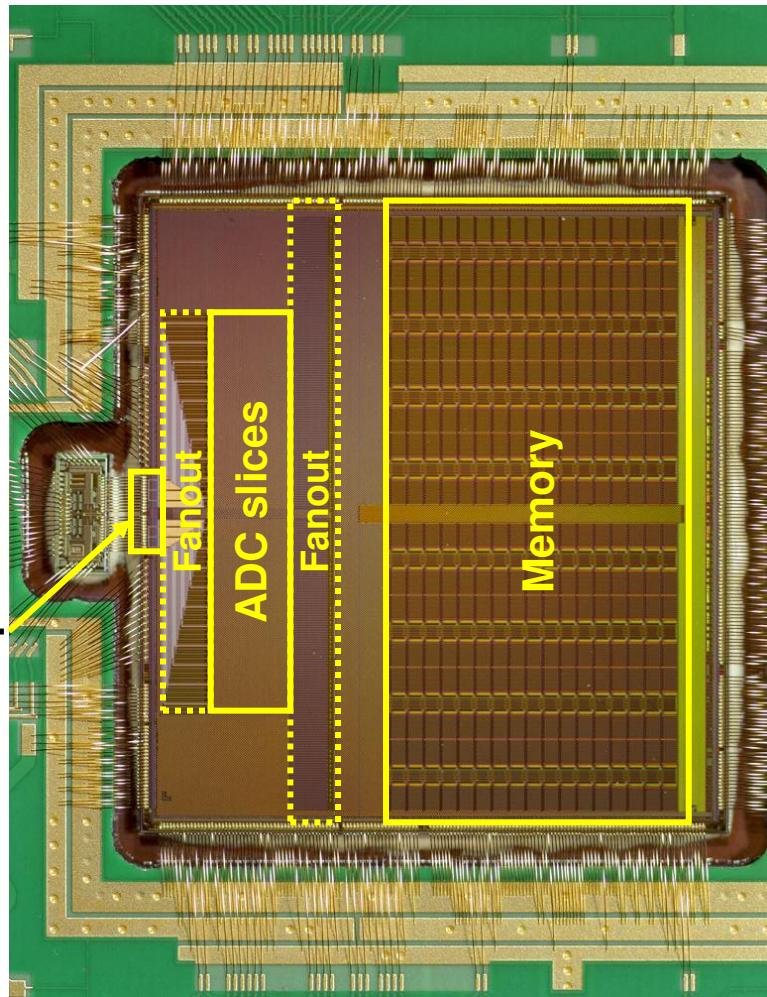
## Example: Clock Generation for 32-way 4-GSa/s ADC



**4 GSa/s:** ~ 1 ps thermal jitter  
**Timing misalignments:** before cal: 10 ps rms, after cal: 0.8 ps rms

# Clock and Signal Distribution

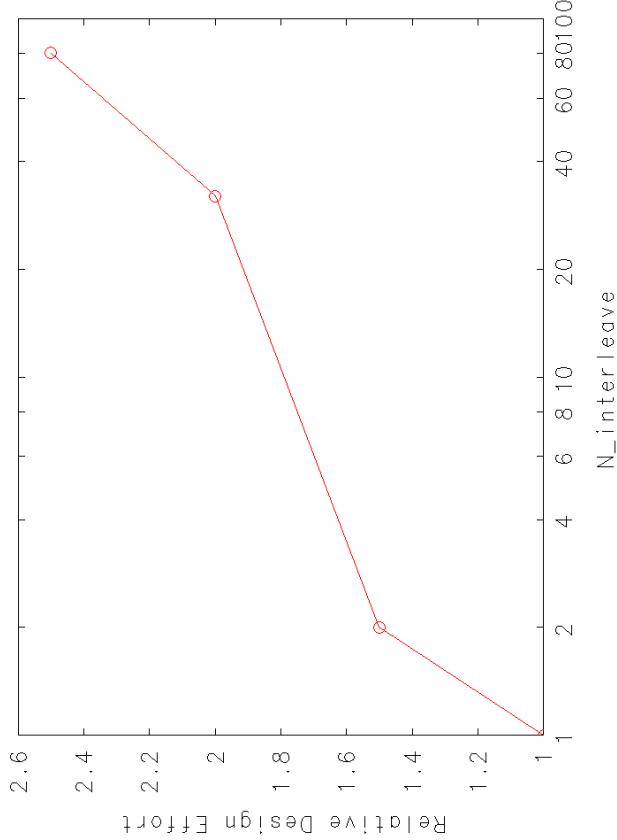
- ◆ Multiple samplers requires distributing clocks
- ◆ Tradeoff between need for proximity of the samplers and physical size of the ADC slices
- ◆ Both clock and analog signal distribution can take a lot of area and power
- ◆ Example: 80-slice ADC:
  - samplers: 1.9 mm wide
  - ADCs: 9 mm
  - Memory 13 mm



# Overhead Factors for Interleaved ADCs

- ◆ Power: Even with a power-efficient ADC slice, you can still have a lot of chip power
  - Example: 32-way, 4-GSa/s ADC
    - 32 ADC slices 1.6 W
    - Samplers + clocks 0.9 W
    - Multiplexors and outputs 1.7 W
    - Total 4.2 W
- ◆ Design Overhead:
  - More optimization variables
  - More circuits that interact
  - More clocks
  - $V_{IN}$  and clock distribution
  - Data collection and multiplexing
  - Calibration
  - Optional: Memory and/or DSP

**Historical Data: Relative Design Time vs.  
Interleave Factor**



## Where Does All That Data Go?

- ◆ Totally application-dependent
- ◆ Off Chip
  - Wide parallel busses (~1 Gb/s per pin) or faster serial ports
  - I/O power can easily be as much as the ADC power
- ◆ On-chip memory
  - Memory power can easily be as much as the ADC power
  - When you need more memory, moving to the next process is a huge redesign for the ADC
- ◆ On-chip DSP
  - A big win if the DSP reduces the amount of data that must be stored or transported off-chip
  - Otherwise, it can be a problem to tie together the ADC process and the DSP process due to different power scaling and development times.

# Trends

- ◆ Much more power-efficient core slices
  - Power-Efficiency FOM has dropped by ~10x since 2002
  - Pipelines and SARs dominate
- ◆ More background cal
  - Making the transition from academia to industry
  - Partly enabled by targeting specific apps like communication channels with somewhat-known signals
- ◆ Interleaving is breaking out of “just for scopes”
  - Lots of papers at ISSCC
  - A startup whose major focus is interleaving existing ADCs
  - Massive interleaving for 12-25 Gb/s wireline links
  - Becoming “just another ADC topology”

## **What is the Future for Interleaved ADCs?**

- ◆ When will all ADCs be interleaved?
  - Never!
  - Design complexity
  - Overhead for power and design time
- ◆ When will time-interleaved ADCs become common?
  - It's happening right now

## Acknowledgements

- ◆ John Corcoran and Robert Neff of Agilent Labs